DISCRETE SEMICONDUCTORS

DATA SHEET

BF1212; BF1212R; BF1212WR N-channel dual-gate MOS-FETs

Product specification

2003 Nov 14





N-channel dual-gate MOS-FETs

BF1212; BF1212R; BF1212WR

FEATURES

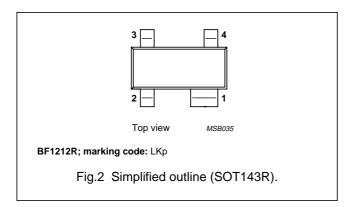
- Short channel transistor with high forward transfer admittance to input capacitance ratio
- · Low noise gain controlled amplifier
- Excellent low frequency noise performance
- Partly internal self-biasing circuit to ensure good cross-modulation performance during AGC and good DC stabilization.

APPLICATIONS

 Gain controlled low noise VHF and UHF amplifiers for 5 V digital and analog television tuner applications.

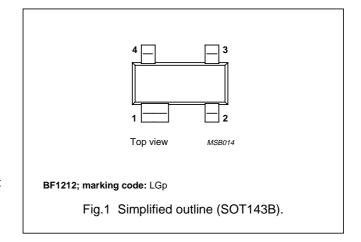
DESCRIPTION

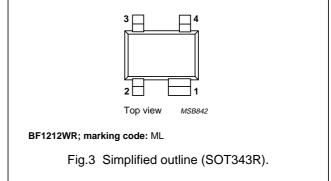
Enhancement type N-channel field-effect transistor with source and substrate interconnected. Integrated diodes between gates and source protect against excessive input voltage surges. The BF1212, BF1212R and BF1212WR are encapsulated in the SOT143B, SOT143R and SOT343R plastic packages respectively.



PINNING

PIN	DESCRIPTION
1	source
2	drain
3	gate 2
4	gate 1





QUICK REFERENCE DATA

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
V _{DS}	drain-source voltage		_	_	6	V
I _D	drain current		_	_	30	mA
P _{tot}	total power dissipation		_	_	180	mW
y _{fs}	forward transfer admittance		28	33	43	mS
C _{ig1-ss}	input capacitance at gate 1		_	1.7	2.2	pF
C _{rss}	reverse transfer capacitance	f = 1 MHz	_	15	30	fF
F	noise figure	f = 800 MHz	_	1.1	1.8	dB
X _{mod}	cross-modulation	input level for k = 1 % at 40 dB AGC	100	104	_	dBμV
Tj	junction temperature		_	_	150	°C

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CAUTION

This product is supplied in anti-static packing to prevent damage caused by electrostatic discharge during transport and handling. For further information, refer to Philips specs.: SNW-EQ-608, SNW-FQ-302A and SNW-FQ-302B.

ORDERING INFORMATION

TYPE NUMBER		PACKAGE	
I I PE NOMBER	NAME	DESCRIPTION	VERSION
BF1212	_	plastic surface mounted package; 4 leads	SOT143B
BF1212R	_	plastic surface mounted package; reverse pinning; 4 leads	SOT143R
BF1212WR	_	plastic surface mounted package; reverse pinning; 4 leads	SOT343R

LIMITING VALUES

In accordance with the Absolute Maximum Rating System (IEC 60134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V _{DS}	drain-source voltage		_	6	V
I _D	drain current (DC)		_	30	mA
I _{G1}	gate 1 current		_	±10	mA
I _{G2}	gate 2 current		_	±10	mA
P _{tot}	total power dissipation				
	BF1212; BF1212R	T _s ≤ 116 °C; note 1	_	180	mW
	BF1212WR	T _s ≤ 122 °C; note 1	_	180	mW
T _{stg}	storage temperature		-65	+150	°C
T _j	junction temperature		_	150	°C

Note

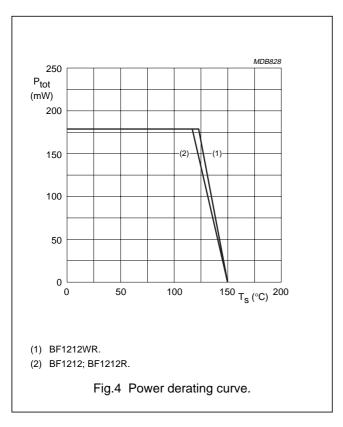
THERMAL CHARACTERISTICS

SYMBOL	PARAMETER	VALUE	UNIT
R _{th j-s}	thermal resistance from junction to soldering point		
	BF1212; BF1212R	185	K/W
	BF1212WR	155	K/W

^{1.} T_s is the temperature of the soldering point of the source lead.

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STATIC CHARACTERISTICS

 $T_j = 25$ °C unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V _{(BR)DSS}	drain-source breakdown voltage	$V_{G1-S} = V_{G2-S} = 0 \text{ V}; I_D = 10 \mu\text{A}$	6	_	V
V _{(BR)G1-SS}	gate 1-source breakdown voltage	$V_{G2-S} = V_{DS} = 0 \text{ V}; I_{G1-S} = 10 \text{ mA}$	6	10	V
V _{(BR)G2-SS}	gate 2-source breakdown voltage	$V_{G1-S} = V_{DS} = 0 \text{ V}; I_{G2-S} = 10 \text{ mA}$	6	10	V
V _{(F)S-G1}	forward source-gate 1 voltage	$V_{G2-S} = V_{DS} = 0 \text{ V}; I_{S-G1} = 10 \text{ mA}$	0.5	1.5	V
V _{(F)S-G2}	forward source-gate 2 voltage	$V_{G1-S} = V_{DS} = 0 \text{ V}; I_{S-G2} = 10 \text{ mA}$	0.5	1.5	V
V _{G1-S(th)}	gate 1-source threshold voltage	$V_{G2-S} = 4 \text{ V}; V_{DS} = 5 \text{ V}; I_D = 100 \mu\text{A}$	0.3	1.0	V
V _{G2-S(th)}	gate 2-source threshold voltage	$V_{G1-S} = 5 \text{ V}; V_{DS} = 5 \text{ V}; I_D = 100 \mu\text{A}$	0.35	1.0	V
I _{DSX}	drain-source current	$V_{G2-S} = 4 \text{ V}; V_{DS} = 5 \text{ V}; R_{G1} = 150 \text{ k}\Omega;$ note 1	8	16	mA
I _{G1-S}	gate 1 cut-off current	V _{G2-S} = V _{DS} = 0 V; V _{G1-S} = 5 V	_	50	nA
I _{G2-S}	gate 2 cut-off current	V _{G1-S} = V _{DS} = 0 V; V _{G2-S} = 4 V	_	20	nA

Note

1. R_{G1} connects G_1 to $V_{GG} = 5$ V.

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DYNAMIC CHARACTERISTICS

Common source; T_{amb} = 25 °C; V_{G2-S} = 4 V; V_{DS} = 5 V; I_D = 12 mA; unless otherwise specified.

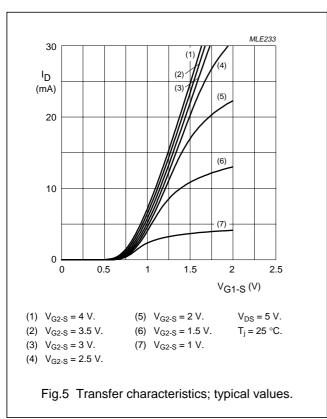
SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
y _{fs}	forward transfer admittance	pulsed; T _j = 25 °C	28	33	43	mS
C _{ig1-ss}	input capacitance at gate 1	f = 1 MHz	_	1.7	2.2	pF
C _{ig2-ss}	input capacitance at gate 2	f = 1 MHz	_	1.1	_	pF
Coss	output capacitance	f = 1 MHz	_	0.9	_	pF
C _{rss}	reverse transfer capacitance	f = 1 MHz	_	15	30	fF
F	noise figure	$f = 11 \text{ MHz}; G_S = 20 \text{ mS}; B_S = 0$	_	4	_	dB
		$f = 400 \text{ MHz}; Y_S = Y_{S \text{ (opt)}}$	_	0.9	1.6	dB
		$f = 800 \text{ MHz}; Y_S = Y_{S \text{ (opt)}}$	_	1.1	1.8	dB
G _{tr}	power gain	$f = 200 \text{ MHz}; G_S = 2 \text{ mS}; B_S = B_{S \text{ (opt)}};$	_	35	_	dB
		$G_L = 0.5 \text{ mS}; B_L = B_{L \text{ (opt)}}$				
		$f = 400 \text{ MHz}; G_S = 2 \text{ mS}; B_S = B_{S \text{ (opt)}};$	_	30	-	dB
		$G_L = 1 \text{ mS}; B_L = B_{L \text{ (opt)}}$				
		$f = 800 \text{ MHz}; G_S = 3.3 \text{ mS}; B_S = B_{S \text{ (opt)}};$	-	25	-	dB
		$G_L = 1 \text{ mS}; B_L = B_{L \text{ (opt)}}$				
X_{mod}	cross-modulation	input level for k = 1%; f _w = 50 MHz;				
		f _{unw} = 60 MHz; note 1				
		at 0 dB AGC	90	-	_	dBμV
		at 10 dB AGC	_	89	_	dBμV
		at 40 dB AGC	100	104	_	dBμV

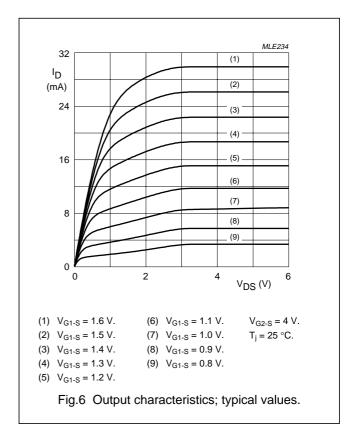
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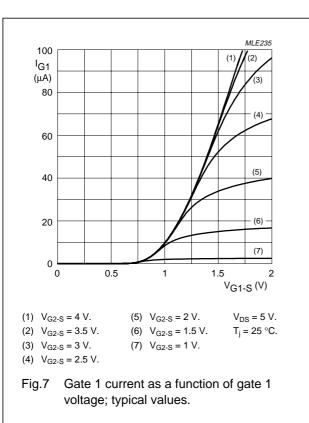
1. Measured in test circuit Fig.21.

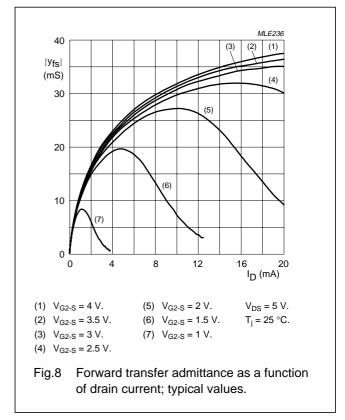
N-channel dual-gate MOS-FETs

BF1212; BF1212R; BF1212WR









N-channel dual-gate MOS-FETs

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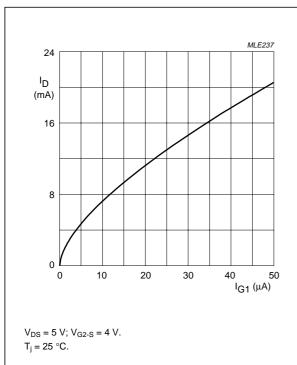


Fig.9 Drain current as a function of gate 1 current; typical values.

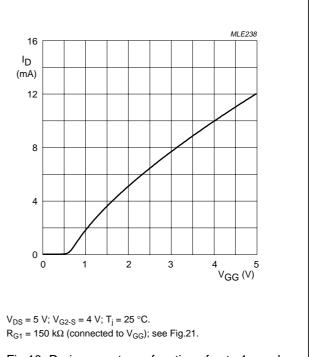
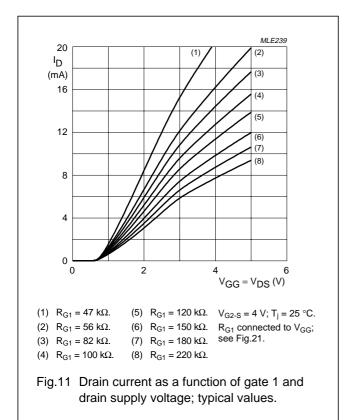
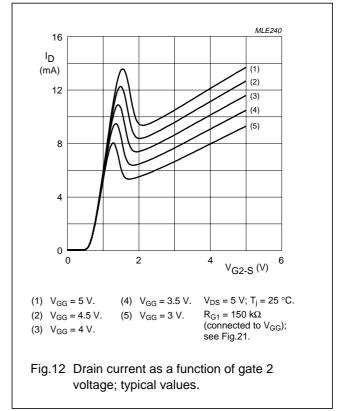


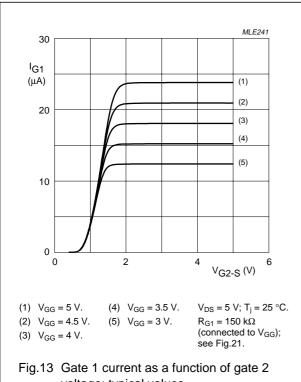
Fig.10 Drain current as a function of gate 1 supply voltage; typical values.



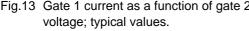


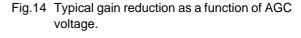
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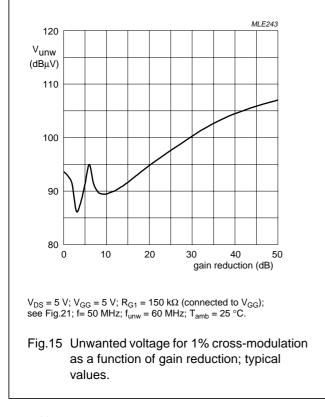
BF1212; BF1212R; BF1212WR

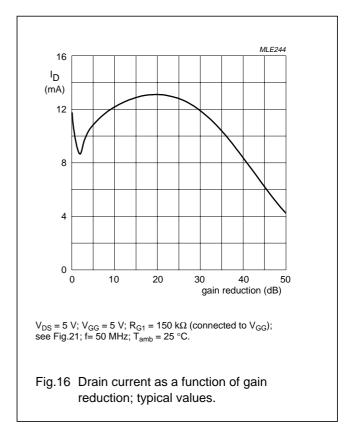


MLE242 gain reduction (dB) -20 -40-60 V_{AGC} (V) $V_{DS} = 5 \text{ V}$; $V_{GG} = 5 \text{ V}$; $R_{G1} = 150 \text{ k}\Omega$ (connected to V_{GG}); see Fig.21; f = 50 MHz; $T_{amb} = 25 ^{\circ}\text{C}$.









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BF1212; BF1212R; BF1212WR

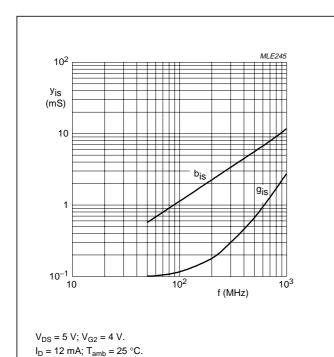


Fig.17 Input admittance as a function of frequency; typical values.

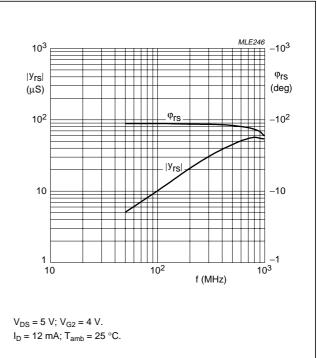


Fig.18 Reverse transfer admittance and phase as functions of frequency; typical values.

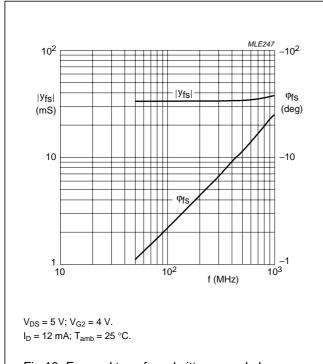
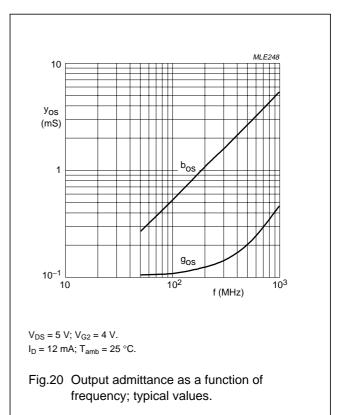


Fig.19 Forward transfer admittance and phase as functions of frequency; typical values.



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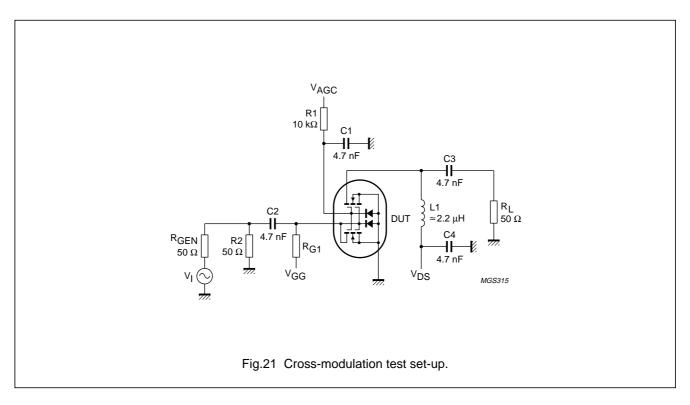


Table 1 Scattering parameters: $V_{DS} = 5 \text{ V}$; $V_{G2-S} = 4 \text{ V}$; $I_D = 12 \text{ mA}$; $T_{amb} = 25 ^{\circ}\text{C}$

	31			, ,	, and			
	S ₁₁		s ₂₁		s ₁₂		s ₂₂	
f (MHz)	MAGNITUDE (ratio)	ANGLE (deg)	MAGNITUDE (ratio)	ANGLE (deg)	MAGNITUDE (ratio)	ANGLE (deg)	MAGNITUDE (ratio)	ANGLE (deg)
50	0.990	-3.39	3.288	176.5	0.0005	86.9	0.990	-1.66
100	0.988	-6.76	3.280	173.0	0.0011	85.6	0.990	-3.30
200	0.983	-13.40	3.261	166.1	0.0021	81.2	0.991	-6.62
300	0.974	-19.86	3.218	159.0	0.0030	77.5	0.991	-9.92
400	0.969	-26.46	3.205	152.6	0.0039	74.6	0.994	-13.30
500	0.958	-32.73	3.141	145.9	0.0045	72.4	0.994	-16.56
600	0.947	-38.83	3.086	139.5	0.0049	70.9	0.993	-19.77
700	0.936	-44.75	3.017	133.1	0.0051	69.5	0.991	-22.78
800	0.924	-50.51	2.949	126.9	0.0051	69.9	0.981	-25.77
900	0.910	-56.18	2.870	120.5	0.0049	69.8	0.984	-28.72
1000	0.896	-61.64	2.785	114.7	0.0045	72.7	0.980	-31.77

Table 2 Noise data: $V_{DS} = 5 \text{ V}$; $V_{G2-S} = 4 \text{ V}$; $I_D = 12 \text{ mA}$; $T_{amb} = 25 ^{\circ}\text{C}$

f	F _{min}	$\Gamma_{\mathbf{c}}$	opt	R _n
(MHz)	(dB)	(ratio)	(deg)	(Ω)
400	0.9	0.695	13.87	28.5
800	1.1	0.634	30.30	32.85

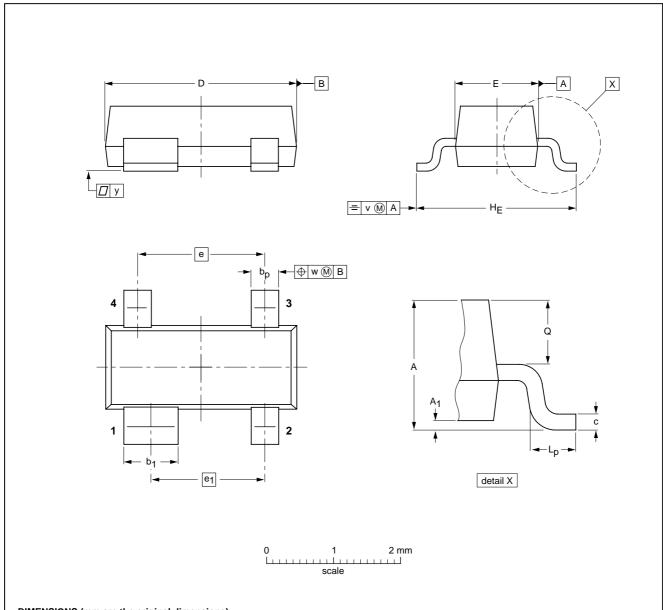
N-channel dual-gate MOS-FETs

BF1212; BF1212R; BF1212WR

PACKAGE OUTLINES

Plastic surface mounted package; 4 leads

SOT143B



DIMENSIONS (mm are the original dimensions)

UNIT	Α	A ₁ max	bp	b ₁	С	D	E	е	e ₁	HE	Lp	Q	v	w	у
mm	1.1 0.9	0.1	0.48 0.38	0.88 0.78	0.15 0.09	3.0 2.8	1.4 1.2	1.9	1.7	2.5 2.1	0.45 0.15	0.55 0.45	0.2	0.1	0.1

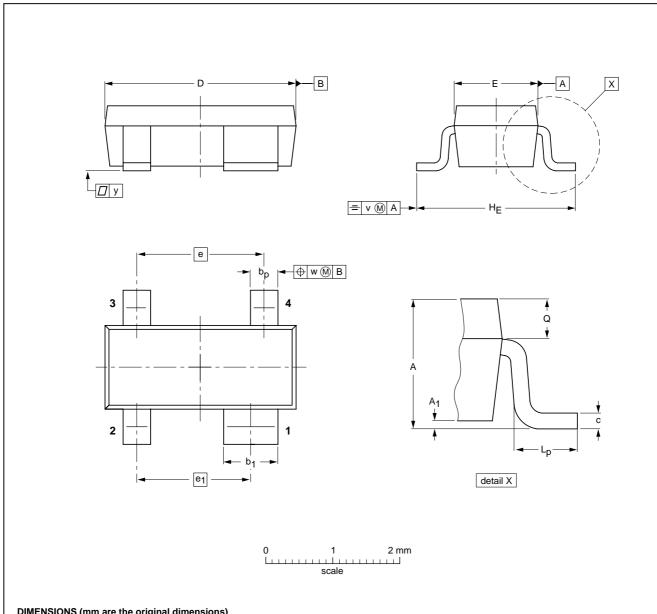
OUTLINE		REFERENCES				ISSUE DATE
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE
SOT143B						97-02-28

N-channel dual-gate MOS-FETs

BF1212; BF1212R; BF1212WR

Plastic surface mounted package; reverse pinning; 4 leads

SOT143R



DIMENSIONS (mm are	the original dimensions)
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UNIT	A	A ₁ max	bp	b ₁	С	D	E	e	e ₁	HE	L _p	Q	v	w	у
mm	1.1 0.9	0.1	0.48 0.38	0.88 0.78	0.15 0.09	3.0 2.8	1.4 1.2	1.9	1.7	2.5 2.1	0.55 0.25	0.45 0.25	0.2	0.1	0.1

OUTLINE		REFER	EUROPEAN	ISSUE DATE			
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUL DATE	
SOT143R			SC-61B			97-03-10 99-09-13	

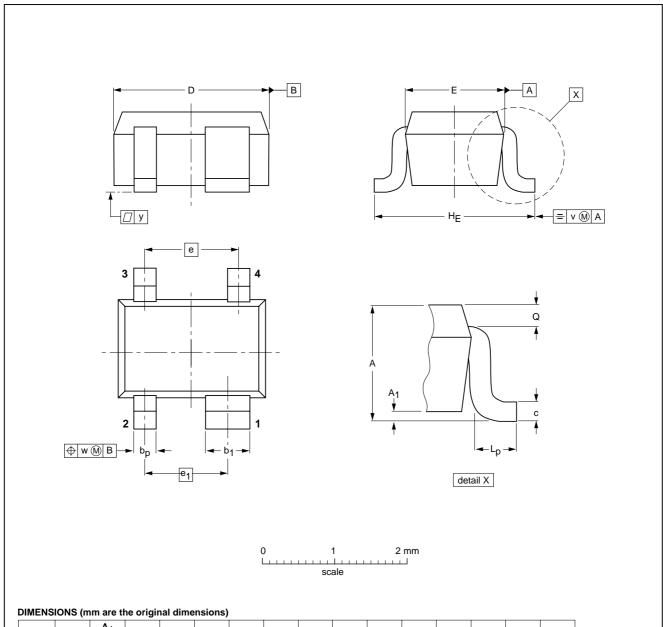
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N-channel dual-gate MOS-FETs

BF1212; BF1212R; BF1212WR

Plastic surface mounted package; reverse pinning; 4 leads

SOT343R



UNIT	A	A ₁ max	bp	b ₁	С	D	E	е	e ₁	HE	Lp	Q	v	w	у
mm	1.1 0.8	0.1	0.4 0.3	0.7 0.5	0.25 0.10	2.2 1.8	1.35 1.15	1.3	1.15	2.2 2.0	0.45 0.15	0.23 0.13	0.2	0.2	0.1

OUTLINE		REFER	EUROPEAN	ICCUE DATE			
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE	
SOT343R						97-05-21	

N-channel dual-gate MOS-FETs

BF1212; BF1212R; BF1212WR

DATA SHEET STATUS

LEVEL	DATA SHEET STATUS ⁽¹⁾	PRODUCT STATUS(2)(3)	DEFINITION
I	Objective data	Development	This data sheet contains data from the objective specification for product development. Philips Semiconductors reserves the right to change the specification in any manner without notice.
II	Preliminary data	Qualification	This data sheet contains data from the preliminary specification. Supplementary data will be published at a later date. Philips Semiconductors reserves the right to change the specification without notice, in order to improve the design and supply the best possible product.
III	Product data	Production	This data sheet contains data from the product specification. Philips Semiconductors reserves the right to make changes at any time in order to improve the design, manufacturing and supply. Relevant changes will be communicated via a Customer Product/Process Change Notification (CPCN).

Notes

- 1. Please consult the most recently issued data sheet before initiating or completing a design.
- 2. The product status of the device(s) described in this data sheet may have changed since this data sheet was published. The latest information is available on the Internet at URL http://www.semiconductors.philips.com.
- 3. For data sheets describing multiple type numbers, the highest-level product status determines the data sheet status.

DEFINITIONS

Short-form specification — The data in a short-form specification is extracted from a full data sheet with the same type number and title. For detailed information see the relevant data sheet or data handbook.

Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 60134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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